

Search Notes

Application/Control No.

10/587,612

Examiner

shih-wen hsieh

Applicant(s)/Patent under
Reexamination

TAMAI ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	36,31,35 100	10/19/2007	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR